Notice of References Cited Application/Control No. 10/573,747 Applicant(s)/Patent Under Reexamination VAN DER SCHAAR ET AL. Examiner Jean B. Corrielus 2611 Applicant(s)/Patent Under Reexamination VAN DER SCHAAR ET AL.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,391,807	06-2008	Lin et al.	375/240.03
*	В	US-6,480,547	11-2002	Chen et al.	375/240.27
*	C	US-2006/0146934	07-2006	Caglar et al.	375/240.12
*	D	US-7,480,252	01-2009	Van Der Schaar, Mihaela	370/252
*	Е	US-7,313,814	12-2007	Zhu et al.	726/6
*	F	US-7,463,683	12-2008	Van Der Schaar et al.	375/240.1
*	G	US-6,907,070	06-2005	Wu et al.	375/240.12
*	Η	US-6,661,841	12-2003	Radha et al.	375/240.1
*	I	US-7,406,176	07-2008	Zhu et al.	380/200
*	J	US-5,515,377	05-1996	Horne et al.	370/395.64
*	К	US-6,996,173	02-2006	Wu et al.	375/240.1
*	L	US-7,203,235	04-2007	Huang et al.	375/240.11
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.